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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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## **ADVANCE TECHNICAL INFORMATION**

# HiPerFET™ MOSFETs ISOPLUS220™

IXFC 26N50 IXFC 24N50

$\mathbf{V}_{ exttt{DSS}}$	<b>I</b> <sub>D25</sub>	R <sub>DS(on)</sub>				
500 V	23 A	0.20 Ω				
500 V	21 A	0.23 Ω				
t <sub></sub> ≤ 250 ns						

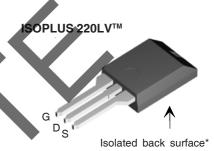
## **Electrically Isolated Back Surface**

N-Channel Enhancement Mode High dV/dt, Low t<sub>...</sub>, HDMOS<sup>™</sup> Family



Symbol	<b>Test Conditions</b>	Maximur	Maximum Ratings			
V <sub>DSS</sub>	$T_J = 25^{\circ}\text{C to } 150^{\circ}\text{C}$ $T_J = 25^{\circ}\text{C to } 150^{\circ}\text{C}; R_{GS} = 1 \text{ M}\Omega$	500 500				
V <sub>GS</sub>	Continuous Transient	±20 ±30				
I <sub>D25</sub>	C	26N50 23 24N50 21	A			
I <sub>DM</sub>	C , JM	26N50 92 24N50 84	A			
AR	C	26N50 26 24N50 24				
<b>E</b> <sub>AR</sub>	$T_{c} = 25^{\circ}C$	30	mJ			
dv/dt	$I_{S} \leq I_{DM}$ , di/dt $\leq 100$ A/ $\mu$ s, $V_{DD} \leq V_{DSS}$ $T_{J} \leq 150$ °C, $R_{G} = 2$ $\Omega$	5	V/ns			
P <sub>D</sub>	$T_{c} = 25^{\circ}C$	230	W			
$T_J$		-55 +150				
T <sub>JM</sub> T <sub>stg</sub>		150 -55 +150				
T <sub>L</sub>	1.6 mm (0.062 in.) from case for 10 s	300	°C			
V <sub>ISOL</sub>	50/60 Hz, RMS t = 1 minute leads-to-ta	ab 2500	V~			
Weight		3	g			

Symbol	<b>Test Conditions</b>	Characteristic Values (T <sub>1</sub> = 25°C, unless otherwise specified)				
		Ü	min.	typ.	max.	
V <sub>DSS</sub>	$V_{GS} = 0 \text{ V}, I_{D} = 250 \text{uA}$		500			V
V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_{D} = 4mA$		2		4	V
I <sub>GSS</sub>	$V_{GS} = \pm 20 V_{DC}, V_{DS} = 0$				±100	nA
I <sub>DSS</sub>	$V_{DS} = 0.8 \bullet V_{DSS}$ $V_{GS} = 0 V$	$T_J = 25^{\circ}C$ $T_J = 125^{\circ}C$			200 1	μA mA
R <sub>DS(on)</sub>	$V_{GS} = 10 \text{ V}, I_{D} = I_{T}$ Notes 1 & 2	26N50 24N50			0.20 0.23	Ω



G = Gate D = Drain S = Source

#### **Features**

- Silicon chip on Direct-Copper-Bond substrate
  - High power dissipation
  - Isolated mounting surface
  - -2500V electrical isolation
- Low drain to tab capacitance(<35pF)</li>
- $^{\bullet}$  Low  $\mathsf{R}_{\scriptscriptstyle{\mathsf{DS}\;(\mathsf{on})}}$  HDMOS  $^{\scriptscriptstyle{\mathsf{TM}}}$  process
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Fast intrinsic Rectifier

## **Applications**

- DC-DC converters
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- AC motor control

### Advantages

- Easy assembly: no screws, or isolation foils required
- Space savings
- High power density
- Low collector capacitance to ground (low EMI)

See IXFH26N50 data sheet for IGBT characteristic curves



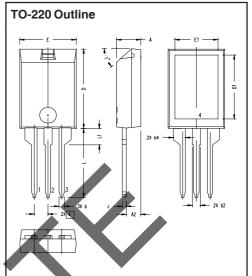
Symbol	Test Conditions	$(T_J = 25^{\circ}C,$		otherwis	istic Values se specified) max.
g <sub>fs</sub>	$V_{DS} = 15 \text{ V}; I_{D} = I_{T}$	Note 1	11	21	S
C <sub>iss</sub>	)			4200	pF
C <sub>oss</sub>	$V_{GS} = 0 \text{ V}, V_{DS} = 25$	5 V, f = 1 MHz		450	pF
$\mathbf{C}_{rss}$	J			135	pF
t <sub>d(on)</sub>	)			16	ns
t <sub>r</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 0$	$0.5 \bullet V_{DSS}, I_{D} = I_{T}$		33	ns
t <sub>d(off)</sub>	$R_{\rm G} = 1 \Omega \text{ (External)}$	,		65	ns
t <sub>f</sub>	)			30	ns
$\mathbf{Q}_{g(on)}$	)			135	nC
$\mathbf{Q}_{gs}$	$V_{GS} = 10 \text{ V}, V_{DS} = 0$	$0.5 \bullet V_{DSS}, I_{D} = I_{T}$		28	nC
$\mathbf{Q}_{gd}$	J			62	nC
R <sub>thJC</sub>				-	0.54 K/W
R <sub>thCK</sub>				0.30	K/W

Source-Drain Diode		(T <sub>.1</sub> = 25°C, u			istic Va	
Symbol	<b>Test Conditions</b>	(1 <sub>J</sub> = 25 0, 0	min.	typ.	max.	illed)
I <sub>s</sub>	$V_{GS} = 0 V$				26	Α
SM	Repetitive; pulse width lim	ited by T <sub>JM</sub>			104	Α
V <sub>sD</sub>	$I_F = I_S$ , $V_{GS} = 0$ V, Note 1				1.5	V
t <sub>rr</sub>	)	T <sub>J</sub> = 25°C T = 125°C			250 400	ns ns
$\mathbf{Q}_{RM}$	$\begin{cases} I_{F} = I_{s}, -di/dt = 100 \text{ A/µs}, \\ V_{R} = 100 \text{ V} \end{cases}$	$T_J = 25^{\circ}C$ $T_J = 125^{\circ}C$		1 2	1	μC μC
I <sub>RM</sub>		$T_{J} = 25^{\circ}C$ $T_{J} = 125^{\circ}C$		10 15		A A

Note: 1. Pulse test,  $t \le 300 \,\mu s$ , duty cycle  $d \le 2 \,\%$ 

2.  $I_T$  test current: IXFC26N50  $I_T = 13A$  IXFC24N50  $I_T = 12A$ 

3. See IXFH26N50 data sheet for characteristic curves.



INCHES MILLIMETERS					
MY2		F2	MILLIN	JE LEK2	
2111	MIM	MAX	MIN	MAX	
А	.157	.197	4.00	5.00	
A2	.098	.118	2.50	3.00	
b	.035	.051	0.90	1.30	
b2	.049	.065	1.25	1.65	
Ь4	.093	.100	2.35	2.55	
0	.028	.039	0.70	1.00	
D	.591	.630	15.00	16.00	
D1	.472	.512	12.00	13.00	
ш	.394	.433	10.00	11.00	
E1	.295	.335	7.50	8.50	
е	.100	BASIC	2.55 BASIC		
L	.512	.571	13.00	14.50	
L1	.118	.138	3.00	3.50	
T.			42.5°	47.5°	

NOTE:

 Bottom heatsink (Pin 4) is electrically isolated from Pin 1, 2, or 3.
This drawing will meet dimensional requirement of JEDEC SS Product Outline TO-273 except D and D1 dimension.